

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

248760US0RDCONT

SERIAL NO.

New Continuation of  
10/188,744

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuo OHBA

FILING DATE

Herewith

2/9/04

GROUP

2822

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>AW</i>	AA	4,792,958	12/20/88	OHBA, et al.	392	45	
	AB	4,809,287	02/28/89	OHBA, et al.	392	45	
	AC	4,835,117	05/30/89	OHBA, et al.	439	40	
	AD	4,949,349	08/14/90	OHBA, et al.	392	45	
	AE	4,910,743	03/20/90	OHBA, et al.	392	45	
	AF	4,928,285	05/22/90	KUSHIBE, et al.	392	45	
	AG	4,893,313	01/09/90	HATAKOSHI, et al.	392	46	
	AH	5,076,800	12/31/91	MILNES, et al.	439	394	
	AI	5,036,521	07/30/91	HATAKOSHI, et al.	562	509	
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	501	71	
	AK	5,042,043	08/20/91	HATANO, et al.	426	72	
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257	13	
	AM	5,079,184	01/07/92	HATANO, et al.	117	102	
<i>AW</i>	AN	5,103,271	04/07/92	IZUMIYA, et al.	257	94	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-34588	01/28/00	JAPAN		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

*William M. Soura*

Date Considered

3-29-05

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Yasuo OHBA</b>			
				FILING DATE <b>Herewith 2/9/04</b>		GROUP <b>2822</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<del>ONE</del>	AA	5,228,044	07/13/93	OHBA	392	45	<del>                    </del>
	AB	5,235,194	08/10/93	IZUMIYA, et al.	257	13	
	AC	5,273,933	12/28/93	HATANO, et al.	119	89	
	AD	5,317,167	05/31/94	IZUMIYA, et al.	257	13	
	AE	5,432,808	07/11/95	HATANO, et al.	392	45	
	AF	5,617,438	04/01/97	HATANO, et al.	392	45	
	AG	5,740,192	04/14/98	HATANO, et al.	392	45	
	AH	5,998,810	12/07/99	HATANO, et al.	257	102	
	AI	6,242,764	06/05/01	Y. OHBA, et al.	257	190	
	AJ	5,990,495	11/23/99	Y. OHBA	257	94	
	AK	5,656,832	06/01/99	Y. OHBA, et al.	257	190	
	AL	5,909,040	06/01/99	Y. OHBA, et al.	257	190	
	AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103	
	AN						
	<b>FOREIGN PATENT DOCUMENTS</b>						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
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	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>[Signature]</i>					Date Considered <b>3-29-05</b>		
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>ms</i>	AA	5,146,465	09/92	KHAN, et al.	585	516	
	AB	6,259,122	07/01	OTA, et al.	257	101	
	AC	5,875,052	02/99	SHMAGIN, et al.	359	244	
	AD	6,306,672 B1	10/01	KIM	438	22	
	AE	6,046,464	04/00	SCHETZINA	257	96	
	AF	6,440,823 B1	08/02	VAUDO, et al.	438	498	
<i>ms</i>	AG	5,929,467	07/99	KAWAI, et al.	257	192	
	AH	5,923,058	07/99	AGARWAL, et al.	257	198	
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

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